

IR LWP & AR FILTERS

GENERAL SPECIFICATION

- Substrate: Silicon Wafer
CZ – N or P type – 1-0-0 or 1-1-1 – 1-30 Ohm/cm
Dia. 100.00mm +0.15 / -0.30mm
Thickness: 0.525mm +/-0.025mm
- Possible Substrate : Germanium Wafer, Sapphire Wafer, etc.
- Durability test method
 - Humidity – MIL-C-48497A 4.5.3.2.
 - Moderate – MIL-C-48497A 4.5.3.3.
 - Adhesion – MIL-C-48497A 4.5.3.1.
 - Water immersion 90 minutes at 100°C
720 hours at 50°C
 - Tape adhesion After both water immersion test

LIST OF PRODUCTS

- IR LWP 5.5um – 0.525T & 0.9T
- IR LWP 6.6um – 0.525T
- IR BBAR 3um ~ 5um – > 98% Hard Coating.
- IR AR 5um ~ 14um – > 75%

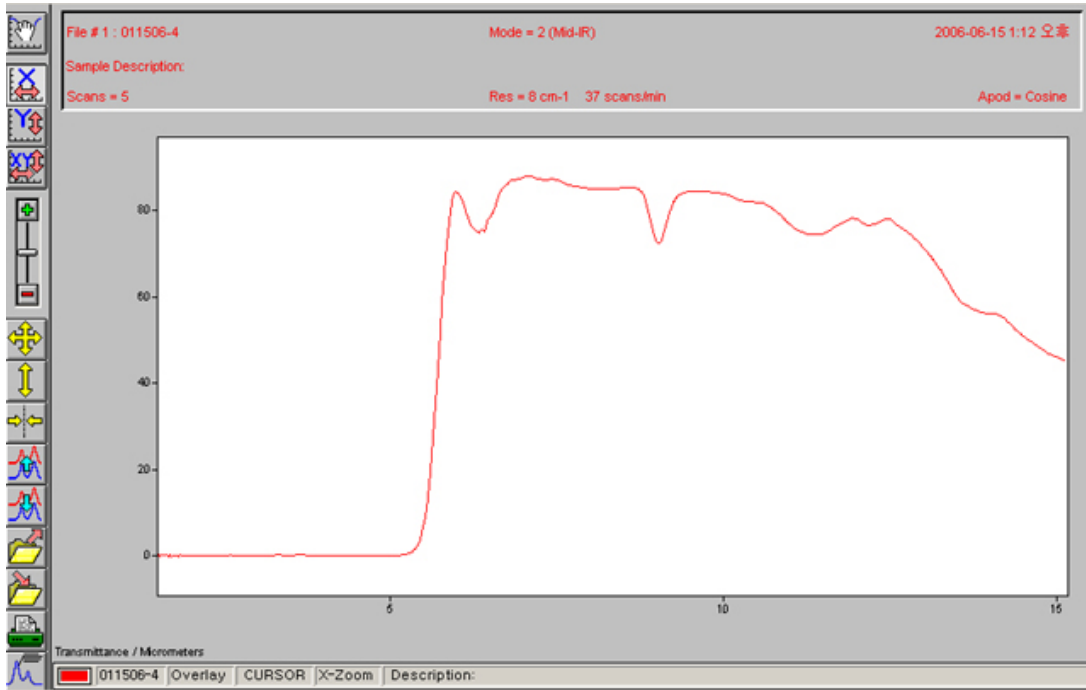
[LWP 5.5 μm : silicon 0.525T]

Cut-on wavelength @ 5% : 5.5 μm +/-0.3 μm

Average Transmittance from 7.5 μm ~ 13.5 μm : >= 77%

From 0.4 μm to 4.8 μm Tave. : <= 0.1%

From 0.4 μm to 4.8 μm Tabs. : <= 1.0%



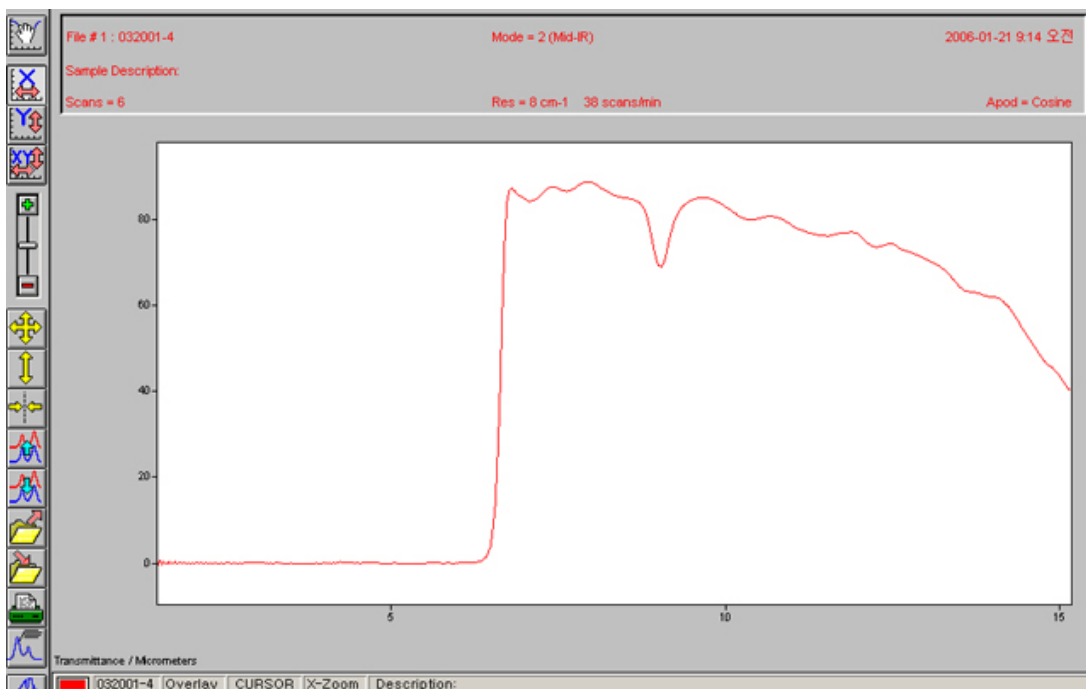
[LWP 6.6 μm : silicon 0.525T]

Cut-on wavelength @ 5% : 6.6 μm +/-0.3 μm

Average Transmittance from 7.5 μm ~ 13.5 μm : >= 77%

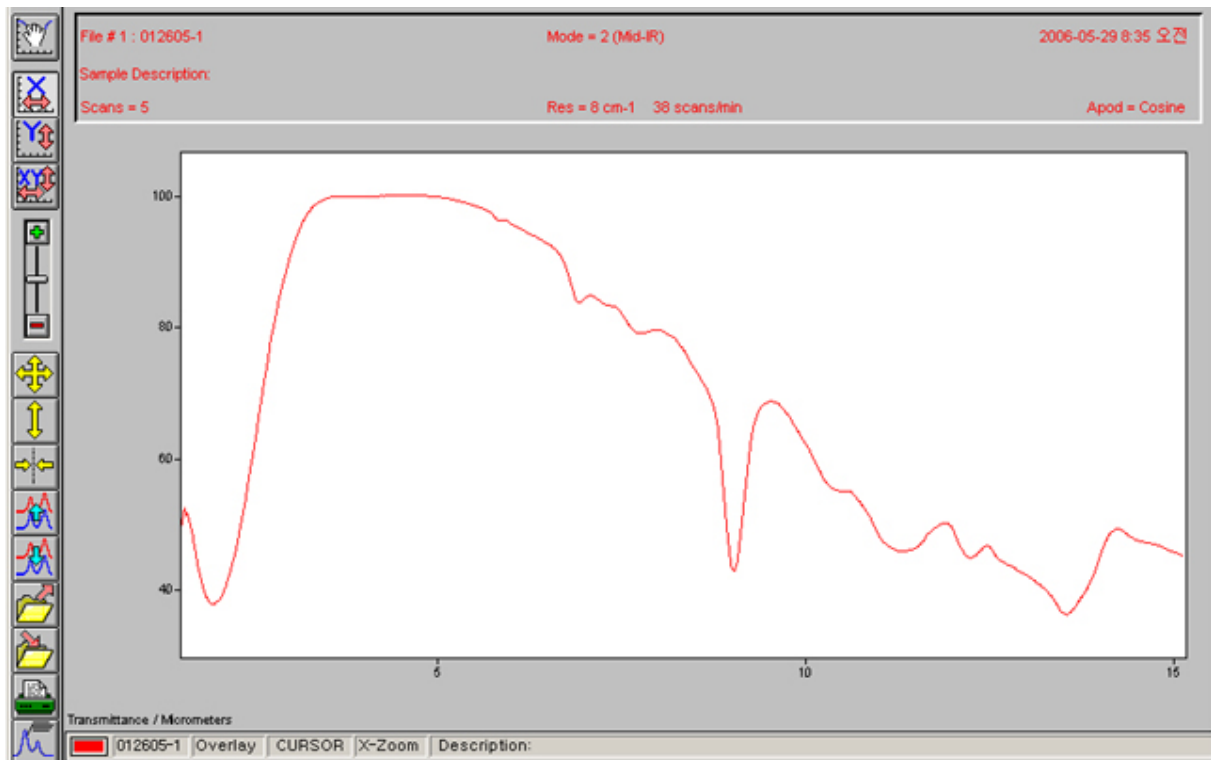
From 0.4 μm to 5.8 μm Tave. : <= 0.1%

From 0.4 μm to 5.8 μm Tabs. : <= 1.0%



[IR BBAR 3.0 μm ~ 5.0 μm : Silicon]

Absolute Transmittance from 3.0 μm ~ 5.0 μm : \geq 98%



[IR AR coating 5.0 μm ~ 14.0 μm : Silicon]

Average Transmittance from 5.0 μm ~ 14.0 μm : \geq 75%

